

METHOD FOR DEFECT MARKING AND ANALYSIS OF THIN FILM HARD DISKS

Abstract

A method for defect location and analysis of thin film hard disks is disclosed. Initially disposed in a disk drive (10) the hard disk (14) is formatted with sector identification lines (24) and data written into data tracks (28). During writing a surface defect (36) is identified by its sector (40), track (44) and byte location (48). The disk (14) is marked such that the defect (36) can be later located. After defect locating erasures for each defect (36) are completed, the disk (14) is removed for microscopic analysis. Ferromagnetic fluid is applied to make the erased tracks visible and is applied to the end of the track erasure of the track (44) that includes the defect (36), without application to the defect (36) itself. As a result, the specific defect (36) is visually located for further analysis in its original condition, without erasure or fluid upon it. A more accurate analysis can be made because of the original condition of the defect (36).

Fig 3